

OptiMOS[™]- 6 Power-Transistor





Product Summary

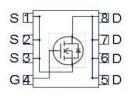
V_{DS}	40	V
$R_{\mathrm{DS(on),max}}$	0.9	mΩ
I _D	120	Α

Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

PG-TDSON-8





Туре	Package	Marking
IAUC120N04S6N009	PG-TDSON-8	6N04N009

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25°C, V _{GS} =10V	120	А
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{2)}$	120	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	480	
Avalanche energy, single pulse ²⁾	E _{AS}	$I_{\rm D}$ =60A, $R_{\rm G,min}$ =25 Ω	400	mJ
Avalanche current, single pulse	IAS	$R_{\rm G,min}$ =25 Ω	60	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25°C	150	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	1.0	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm ² cooling area ³⁾	-	-	50	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0V, I _D = 1mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=90\mu{\rm A}$	2.2	2.8	3.4	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	1	1	1	μΑ
		$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	1	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	1	1	100	nA
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	V _{GS} =7V, I _D =60A	1	0.95	1.1	mΩ
		V _{GS} =10V, I _D =60A	-	0.75	0.9	
Gate resistance ²⁾	R _G		-	0.9	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C_{iss}		-	5530	7360	pF
Output capacitance	Coss	V _{GS} =0V, V _{DS} =25V, f=1MHz	-	1550	2070	
Reverse transfer capacitance	C _{rss}		-	108	125	
Turn-on delay time	$t_{\rm d(on)}$		-	10	_	ns
Rise time	t_{r}	V _{DD} =20V, V _{GS} =10V,	-	6	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =120A, $R_{\rm G}$ =3.5 Ω	-	22	_	
Fall time	t_{f}		-	11	-	
Gate Charge Characteristics ²⁾						
Gate to source charge	Q _{gs}		-	25	33	nC
Gate to drain charge	Q_{gd}	$V_{\rm DD}$ =32V, $I_{\rm D}$ =120A, $V_{\rm GS}$ =0 to 10V	-	15	28	
Gate charge total	Q_g		-	76	115	
Gate plateau voltage	$V_{ m plateau}$		-	4.5	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T -25°C	-	-	120	Α
Diode pulse current ²⁾	I _{S,pulse}	- T _C =25°C	-	-	480	
Diode forward voltage	V _{SD}	V _{GS} =0V, / _F =60A, T _j =25°C	-	0.8	1.1	V
Reverse recovery time ²⁾	t _{rr}	V_R =20V, I_F =120A, di_F/dt =100A/ μ s	-	60	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	73	-	nC

¹⁾ Current is limited by package; with an $R_{\rm thJC}$ = 1 K/W the chip is able to carry 300 A at 25 °C.

²⁾ The parameter is not subject to production test- verified by design/characterization.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

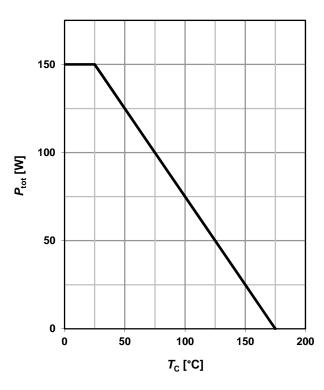


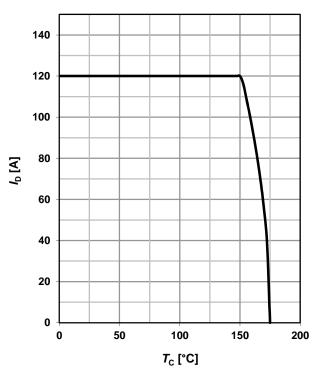
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10 \text{ V}$$

2 Drain current

$$I_{\rm D} = f(T_{\rm C}); \ V_{\rm GS} = 10 \ {\rm V}$$





3 Safe operating area

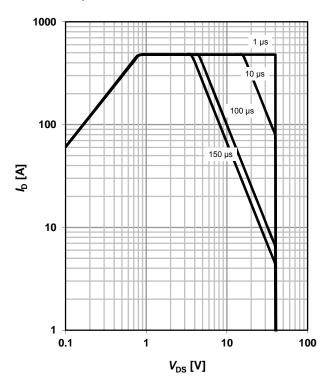
$$I_{\rm D} = {\rm f}(V_{\rm DS}); T_{\rm C} = 25~{\rm ^{\circ}C}; D = 0$$

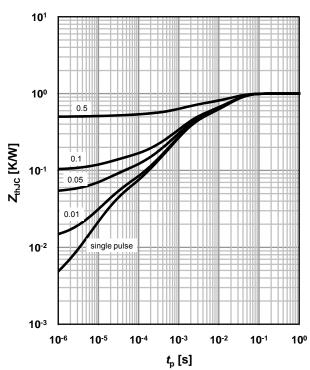
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D=t_p/T$



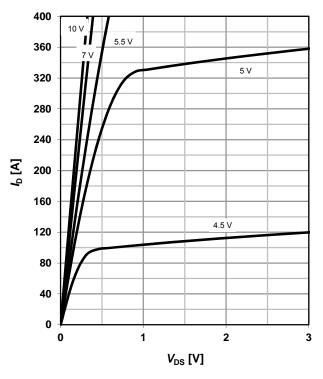




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_i = 25 °C$

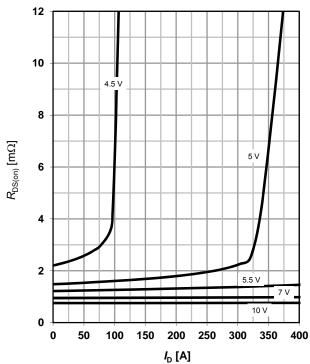
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 °C$

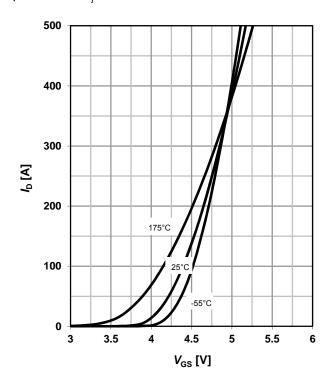
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

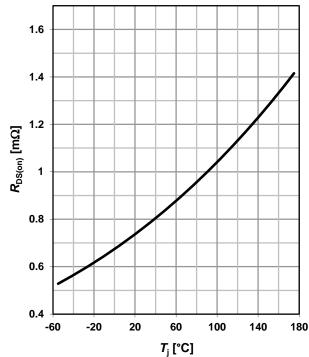
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 60 \text{ A}; V_{GS} = 10 \text{ V}$$





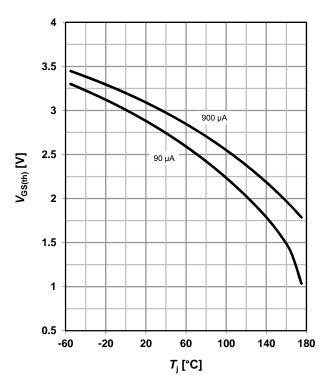
9 Typ. gate threshold voltage

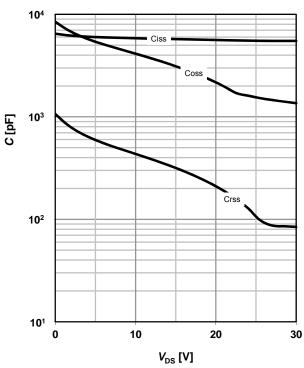
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristics

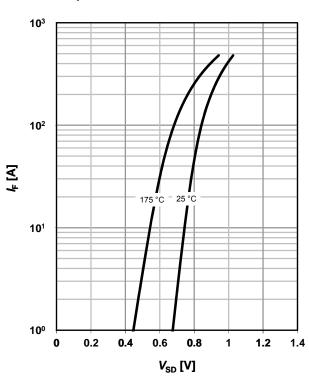
 $IF = f(V_{SD})$

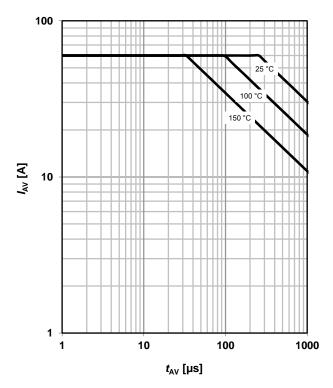
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{i(start)}





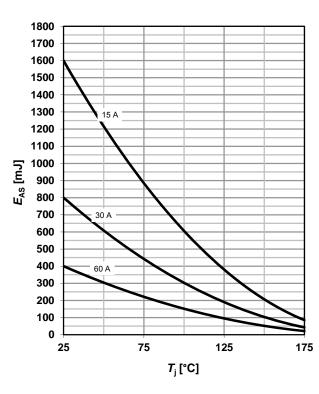


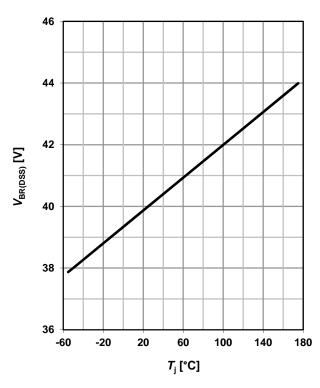
13 Avalanche energy

$E_{AS} = f(T_i)$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

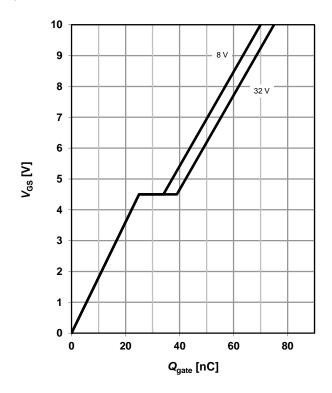




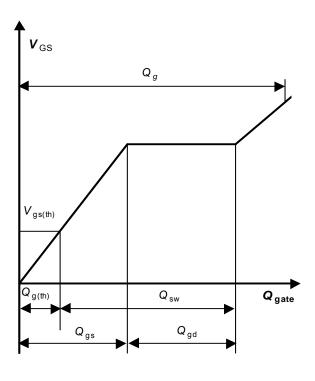
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 40 A pulsed$

parameter: V_{DD}



16 Gate charge waveforms





Published by Infineon Technologies AG 81726 Munich, Germany

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Revision History

Version	Date	Changes		
Revision 1.0	2018-09-27	Final Data Sheet		